!AP9 Rec'd PCT/PTO 2 4 MAR 2006"

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UNITED STATES PATENT & TRADEMARK OFFICE

Re: Application of: Heinrich ULRICH et al.

Serial No.: To Be Assigned

Filed: Herewith as national phase of International

Application No. PCT/EP2004/052296, filed 23 September

2004

For: SCANNING MICROSCOPE WITH EVANESCENT

WAVE ILLUMINATION

Customer No.: 23280

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

March 22, 2006

Sir:

In accordance with the provisions of 37 C.F.R. § 1.97, Applicant hereby makes of record the documents listed on the accompanying PTO-1449 Form (1 page) for consideration by the Examiner in connection with the examination of the above-identified patent application. While the references are being submitted herewith, some or all of the references may not constitute prior art under the U.S. patent laws.

This Information Disclosure Statement is filed under 37 C.F.R. §1.97 (b), before the mailing date of a First Office Action, therefore no fee is believed due. In the event any

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additional fee is due in connection with this response or if any fee has been overpaid, the deficiency or overpayment should be charged to our Deposit Account No. 50-0552.

It is respectfully requested that the references cited in the accompanying PTO-1449 form be considered and made of record. It is respectfully submitted that the pending claims are patentable over all of the references made of record at this time.

Respectfully submitted,
DAVIDSON, DAVIDSON & KAPPEL, LLC

Erik R. Swanson

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DAVIDSON, DAVIDSON & KAPPEL, LLC 485 Seventh Avenue, 14th Floor New York, New York 10018 (212) 736-1940 FORM PTO-1449 (REV. 7-80) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

APPLICATION NO

5005.1111

To be assigned

LIST OF PRIOR ART CITED BY APPLICANT

APPLICANT
Heinrich ULRICH et al.

GROUP

(Use several sheets if necessary)

FILING DATE
Herewith

To be assigned

U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB- CLASS | FILING DATE IF APPROPRIATE |
|----------------------|-----|-----------------|---------------|---------------|-------|--|----------------------------|
| | A01 | 2003/058530 A1 | Mar. 27, 2003 | Kawano | 359 | 385 | |
| | A02 | 6,255,642 B1 | Jul. 3, 2001 | Cragg et al. | 250 | 216 | |
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| | A10 | | | | | | |

FOREIGN PATENT DOCUMENTS

| | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUB- CLASS | TRANSLATION | |
|---------|------------------|---------------|-------------|----------|---------------|---|----|
| | | | | | | YES | NO |
| A11 | DE 199 02 234 A1 | Feb. 24, 2000 | DE-Germany | | | See Intl. Search Report for PCT/EP2004/052296; see English Abstract | |
| A12 | | | | | | | |
| A13 | | | · · · · · · | <u> </u> | | | |
| A14 | | | | | | | |

| | OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | |
|-----|--|--|--|--|--|--|--|
| A15 | V. Protasenko et al.: "Enhancement and quenching of the fluorescence of single CdSe/ZnS quantum dots studied by confocal apertureless near-field scanning optical microscope"; Proceedings of SPIE Vol. 5188 Advanced Characterization Techniques for Optics, Semiconductors, and Nanotechnologies, November 2003, pp. 254-263 | | | | | | |
| A16 | S. Kawata et al.: "Near-Field Scanning Optical Microscope with a Laser Trapped Probe"; Jpn. J. Appl. Phys. Vol. 33 (1994), Part 2, No. 12A, 1 December 1994, pp. L 1725-L 1727 | | | | | | |
| A17 | International Search Report for PCT/EP2004/052296 (3 pages) | | | | | | |
| A18 | | | | | | | |
| A19 | | | | | | | |
| A20 | | | | | | | |

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.